**REMARKS** 

Applicants thank the Examiner for acknowledging receipt of Applicants foreign

priority documents that have been submitted pursuant to 35 U.S.C. §119. Applicants have

modified the title of the invention in accordance with the Examiners request. Applicants also

thank the Examiner for the indication of allowable subject matter in claims 24-49. In light of

the foregoing Amendments, Applicants submit that the remaining claims now also stand in

condition for allowance.

More specifically, Applicants have modified independent claim 1 to further require

that an electric current, voltage or resistance associated with the electrolytic polishing is used

in the determination of when the desired thickness has been removed. Applicants

respectfully submit that the prior art of record provides no teaching or suggestion whatsoever

regarding this advance in the art. More specifically, Wang merely describes measuring the

optical reflectivity in order to determine when sufficient polishing has been performed.

There is simply no teaching nor suggestion whatsoever in Wang or any of the other remaining

references regarding Applicants improved polishing method, wherein the end point

determination for a portion of the overall surface can be more reliably determined in a quick

and convenient manner.

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In light of the foregoing, Applicants submit that the application now stands in condition for allowance.

Respectfully submitted,

Date: April 22, 2004

Robert J. Depke

HOLLAND & KNIGHT LLC 131 S. Dearborn, 30<sup>th</sup> Floor Chicago, Illinois 60603

(Reg. #37,667

Tel: (312) 263-3600 Attorney for Applicant